## Application/Control No. Applicant(s)/Patent Under Reexamination 10/052.989 HSIEH ET AL. Notice of References Cited Examiner Art Unit Page 1 of 1 DAVID VU 2818 **U.S. PATENT DOCUMENTS** Document Number Date Classification Country Code-Number-Kind Code MM-YYYY US-6,358,836 03-2002 438/618 Lu et al. US-6,348,399 02-2002 438/616 В Lin, Chun Hung US-5.903.058 05-1999 Akram, Salman 257/778 С 438/614 US-6,489,229 12-2002 Sheridan et al. D 438/455 US-6,130,141 10-2000 Degani et al. Ε US-6,576,545 438/624 F 06-2003 Hopper et al. G US-Н USj US-US-Κ US-L US-FOREIGN PATENT DOCUMENTS Document Number Date Country Name Classification Country Code-Number-Kind Code MM-YYYY Ν O Р Q R s Т **NON-PATENT DOCUMENTS** Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) U W

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

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